Special Issue

Advances in the Measurement and Application of Particle Tracking

Message from the Guest Editors

This Special Issue is dedicated to the scientific development and application of particle tracking technologies that are predominantly utilized in the study of dynamic systems. A class of diverse and often complementary techniques exist to interrogate these systems, often based on hard field measurements (positron emission particle tracking and derivatives, radioactive particle tracking, X- and gamma-ray, neutron transmission imaging and/or tomography, etc.), optical techniques (particle image velocimetry, particle tracking velocimetry, etc.), and traditional tracer tracking methodologies.

Contributions in the following key themes are invited:

Advances in particle tracking measurement;

Novel particle tracking methodologies;

Multi-modal or complimentary particle tracking and flow measurements;

Benchmarking and validation of particle tracking techniques and models;

Particle tracking in numerical simulation;

Applications of particle tracking measurement and simulation.

Guest Editors

Prof. Dr. Andy Buffler

Dr. Tom Leadbeater

Dr. Lianfu Han

Deadline for manuscript submissions

closed (20 September 2023)

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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